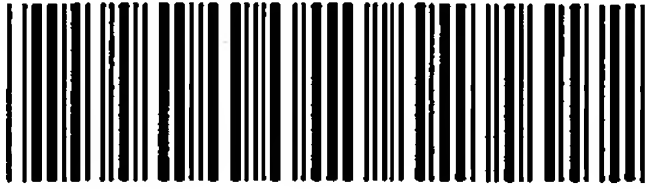


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/623,414	DEEM ET AL.	
	Examiner	Art Unit	
	Henry K. Choe	2817	

SEARCHED			
Class	Subclass	Date	Examiner
330	151	12/14/05	H.C.
"	149	"	"
375	297	"	"
455	63	12/15/05	"

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Tru search (East)	3/15/05	H.C.
NPL (IEEE)	"	"